

Search Notes

Application/Control No.

10/056,821

Examiner

Susan Y. Chen

Applicant(s)/Patent under
Reexamination

KEE ET AL.

Art Unit

2161

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
707	10, 103X	6/7/2006	TYC
707	200,201	6/7/2006	TYC
709	223	6/7/2006	TYC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated text search on East DB	6/7/2006	TYC
NPL-Google, IEEE, ACM search	6/6/2006	TYC
STIC database search	6/7/2006	TYC
Consults with primary examiner - Wen. T. Lin at 709 for class crossreference	6/7/2006	TYC
Interference history search attached	6/8/2006	TYC